Approved by:

Checked by:

Issued by:

# **SPECIFICATION**

## PRODUCT: SAW FILTER

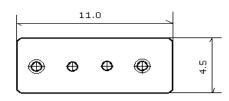
MODEL: HD F858CF11

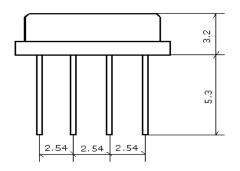


SHOULDER ELECTRONICS LIMITED

## **1. Package Dimension**

(**F-11**)





#### Unit:mm

NO	Function
1	Input
2	Ground
3	Ground
4	Output

# 2. Marking

#### **HD F858C**

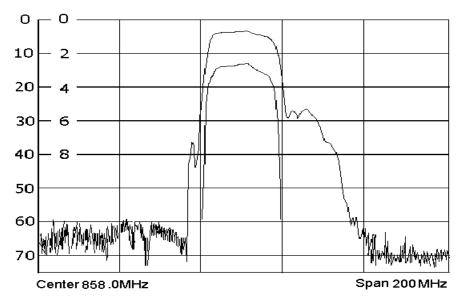
- 1.Color: Black or Blue
- 2.858: Center Frequency(MHz)
- 3.Performance
- 3.1 Application
  - Low-Loss SAW Filter of cordless system.
  - Center Frequency:858MHz
- 3.2 Maximum Rating

Operation Temperature Range	-20°C to +50°C
Storage Temperature Range	-40°C to +85°C
DC. Permissive Voltage	0 V DC. max.
Maximum Input Power	5dBm

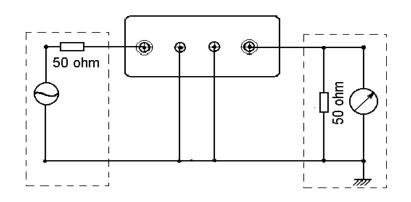
**3.3 Electronic Characteristics** 

Item	Specification
Center Frequency(fo)	858.0MHz
Insertion Loss	
Fo±4 MHz	5.0 dB max
1.)Fo-36.0 MHz	50 dB min
2.)Fo-200~36 MHz	40 dB min
3.)Fo+100~300 MHz	50 dB min
Ripple deviation (854~862MHz)(dB)	2.0max
Input/output Impedance(Nominal)	50 Ω
Operating Temperature Range	0°C to +50°C

3.4 Frequency Characteristics







### 4. ENVIRONMENTAL CHARACTERISTICS

4-1 High temperature exposure

Subject the device to  $+85^{\circ}$ C for 16 hours. Then release the filter into the room conditions for 24 hours prior to the measurement. It shall fulfill the

specifications in table 1.

4-2 Low temperature exposure

Subject the device to  $-20^{\circ}$ C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in table 1.

4-3 Temperature cycling

Subject the device to a low temperature of -40 °C for 30 minutes. Following by a high temperature of +80 °C for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in table 1.

4-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at  $260^{\circ}$ C  $\pm 10^{\circ}$ C for  $10\pm 1$  sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in table 1.

4-5 Solderability

Subject the device terminals into the solder bath at  $245^{\circ}$ C  $\pm 5^{\circ}$ C for 5s, More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in table 1.

4-6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. the device shall fulfill the specifications in table 1.

4-7 Vibration

Subject the device to the vibration for 1 hour each in x,y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in table 1.

#### 4-8 Lead fatigue

4-8-1 Pulling test

Weight along with the direction of lead without an shock 1kg. The device shall satisfy all the initial Characteristics.

4-8-2 Bending test

Lead shall be subject to withstand against  $90^{\circ}$ C bending with 450g weight in the direction of thickness. This operation shall be done toward both direction. The device shall show no evidence of damage and shall

#### 5. REMARK

5.1 Static voltage

Static voltage between signal load & ground may cause deterioration & destruction of the component. Please avoid static voltage.

5.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

5.3 Soldering

Only leads of component may be soldered . Please avoid soldering another part of component.